



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor : Frank Pietzschmann

Applic. No.: 09/923,720

Filed : August 6, 2001

Title : Test Apparatus for Semiconductor Circuit
and Method of Testing Semiconductor
Circuits

Examiner : Emily Y. Chan Art Unit: 2829

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REQUEST TO APPROVE DRAWING CHANGES

Hon. Commissioner for Patents,

S i r :

Please approve the drawing changes that are marked in red on the accompanying "Annotated Sheet Showing Changes" of Fig. 1. Indicators for the planarizer 7 and the test head 1 were added to Fig. 1. A formal "Replacement Sheet" of amended Fig. 1 is also enclosed.

Respectfully submitted,



For Applicant

July 29, 2003

RALPH E. LOCHER
REG. NO. 41,947

Lerner and Greenberg, P.A.
P.O. Box 2480
Hollywood, Florida 33022-2480
Tel.: (954) 925-1100
Fax: (954) 925-1101